

ON Semiconductor®

FDN357N N-Channel Logic Level Enhancement Mode Field Effect Transistor

General Description

SuperSOTTM-3 N-Channel logic level enhancement mode power field effect transistors are produced using ON Semiconductor's proprietary, high cell density, DMOS technology. This very high density process is especially tailored to minimize on-state resistance. These devices are particularly suited for low voltage applications in notebook computers, portable phones, PCMCIA cards, and other battery powered circuits where fast switching, and low in-line power loss are needed in a very small outline surface mount package

Features

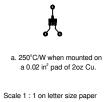
- $\label{eq:linear_line$
- Industry standard outline SOT-23 surface mount package using proprietary SuperSOT[™]-3 design for superior thermal and electrical capabilities.
- High density cell design for extremely low R_{DS(ON)}.
- Exceptional on-resistance and maximum DC current capability.

s	DT-23	SuperSOT [™] -6	SuperSOT [™] -8	SO-8	SOT-223	SOIC-16
		D 351	s			
Absol	-	r _{SOT} ™-3 G um Ratings ⊺₄=		ted	GS	
	-	rSOT -3	- 25°C unless other wise no	ted	G S FDN357N	
ymbol	ute Maximu	$\frac{1}{1000} \text{ mRatings } T_A = \frac{1}{1000}$		ted		
ymbol _{DSS}	ute Maximu Parameter Drain-Source	$\frac{1}{1000} \text{ mRatings } T_A = \frac{1}{1000}$	= 25°C unless other wise no	ted	FDN357N	Units
DSS GSS	Parameter Drain-Source Gate-Source	SOT -3 Im Ratings T _A = e Voltage	= 25°C unless other wise no	ted	FDN357N 30	Units V
bymbol DSS GSS	Parameter Drain-Source Gate-Source	SOT -3 um Ratings T _A = e Voltage e Voltage - Continuous	= 25°C unless other wise no	ted	FDN357N 30 ±20	Units V V V
Symbol DSS GSS	Ute Maximu Parameter Drain-Source Gate-Source Drain/Outpu	SOT -3	= 25°C unless other wise no	ted	FDN357N 30 <u>+20</u> 1.9	Units V V V
gymbol JDSS GSS	Ute Maximu Parameter Drain-Source Gate-Source Drain/Outpu	rSOT3	= 25°C unless other wise no s	ted	FDN357N 30 ±20 1.9 10	Units V V A
ymbol DSS GSS D	Ute Maximu Parameter Drain-Source Gate-Source Drain/Outpu Maximum Pe	rSOT3	= 25°C unless other wise no s s (Note 1a) (Note 1b)	ted	FDN357N 30 ±20 1.9 10 0.5	Units V V A
Symbol (DSS (GSS))))))))))))))))))	Ute Maximu Parameter Drain-Source Gate-Source Drain/Outpu Maximum Pe	SOT -3 T _A = Voltage Voltage - Continuous Current - Continuou - Pulsed ower Dissipation	= 25°C unless other wise no s s (Note 1a) (Note 1b)	ted	FDN357N 30 ±20 1.9 10 0.5 0.46	Units V V V A W
Symbol (DSS (GSS D D D C,,T _{STG}	Parameter Drain-Source Gate-Source Drain/Output Maximum Per Operating ar L CHARACTI	SOT -3 T _A = Voltage Voltage - Continuous Current - Continuou - Pulsed ower Dissipation	= 25°C unless other wise no	ted	FDN357N 30 ±20 1.9 10 0.5 0.46	Units V V V A W

Symbol	Parameter	Conditions	Min	Тур	Max	Units
OFF CHAF	RACTERISTICS	<u>.</u>				•
BV _{DSS}	Drain-Source Breakdown Voltage	$V_{GS} = 0 V, I_{D} = 250 \mu A$	30			V
$\Delta BV_{DSS}/\Delta T_{J}$	Breakdown Voltage Temp. Coefficient	$I_{\rm D}$ = 250 µA, Referenced to 25 °C		36		mV/ °C
I _{DSS}	Zero Gate Voltage Drain Current	$V_{\rm DS} = 24 \text{ V}, \ V_{\rm GS} = 0 \text{ V}$			1	μA
		T _J = 55°C			10	μA
I _{GSSF}	Gate - Body Leakage, Forward	$V_{GS} = 20 \text{ V}, V_{DS} = 0 \text{ V}$			100	nA
I _{GSSR}	Gate - Body Leakage, Reverse	$V_{GS} = -20 \text{ V}, V_{DS} = 0 \text{ V}$			-100	nA
ON CHARA	ACTERISTICS (Note)					
V _{GS(th)}	Gate Threshold Voltage	$V_{\rm DS} = V_{\rm GS}, \ I_{\rm D} = 250 \ \mu A$	1	1.6	2	V
$\Delta V_{GS(th)} / \Delta T_J$	Gate Threshold Voltage Temp. Coefficient	$I_D = 250 \ \mu\text{A}$, Referenced to $25 \ ^{\circ}\text{C}$		-3.6		mV/ °C
R _{DS(ON)}	Static Drain-Source On-Resistance	$V_{GS} = 4.5 \text{ V}, I_{D} = 1.9 \text{ A}$		0.081	0.09	Ω
		T _J =125°C		0.11	0.14	
		$V_{GS} = 10 \text{ V}, I_{D} = 2.2 \text{ A}$		0.053	0.06	
I _{D(ON)}	On-State Drain Current	$V_{GS} = 4.5 \text{ V}, V_{DS} = 5 \text{ V}$	5			Α
9 _{FS}	Forward Transconductance	$V_{\rm DS} = 5 \text{ V}, \ I_{\rm D} = 1.9 \text{ A}$		5		S
DYNAMIC	CHARACTERISTICS					
C _{iss}	Input Capacitance	$V_{DS} = 10 \text{ V}, V_{GS} = 0 \text{ V},$ f = 1.0 MHz		235		pF
C _{oss}	Output Capacitance	f = 1.0 MHz		145		pF
C _{rss}	Reverse Transfer Capacitance			50		pF
SWITCHIN	G CHARACTERISTICS (Note)					
t _{D(on)}	Turn - On Delay Time	$V_{DD} = 10 \text{ V}, \ I_{D} = 1 \text{ A},$		5	10	ns
ţ	Turn - On Rise Time	$V_{GS} = 10 \text{ V}, \text{ R}_{GEN} = 6 \Omega$		12	22	ns
t _{D(off)}	Turn - Off Delay Time			12	22	ns
t _r	Turn - Off Fall Time			3	8	ns
Qg	Total Gate Charge	$V_{DS} = 10 \text{ V}, \text{ I}_{D} = 1.9 \text{ A},$ $V_{GS} = 5 \text{ V}$		4.2	5.9	nC
Q _{gs}	Gate-Source Charge			1.3		nC
Q_{gd}	Gate-Drain Charge			1.7		nC
DRAIN-SO	URCE DIODE CHARACTERISTICS AND M	AXIMUM RATINGS	T			
I _s	Maximum Continuous Drain-Source Diode For	1			0.42	Α
V _{SD}	Drain-Source Diode Forward Voltage $V_{GS} = 0 V$, $I_{S} = 0.42 A$ (Note)			0.71	1.2	V

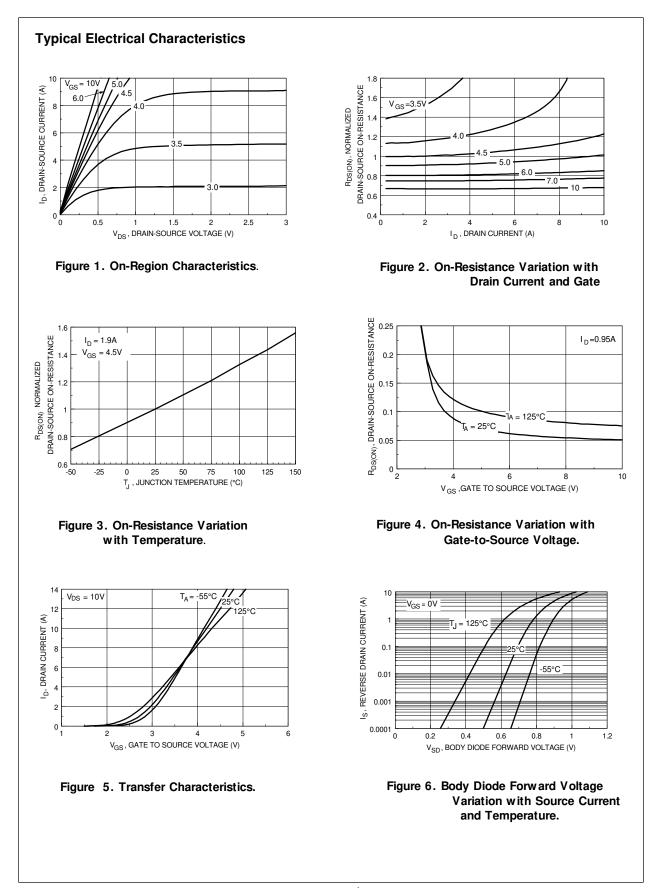
1. R_{avt} is the sum of the junction-to-case and case-to-ambient thermal resistance where the case thermal reference is defined as the solder mounting surface of the drain pins. R_{avc} is guaranteed by design while ${\rm R}_{_{\rm \theta CA}}$ is determined by the user's board design.

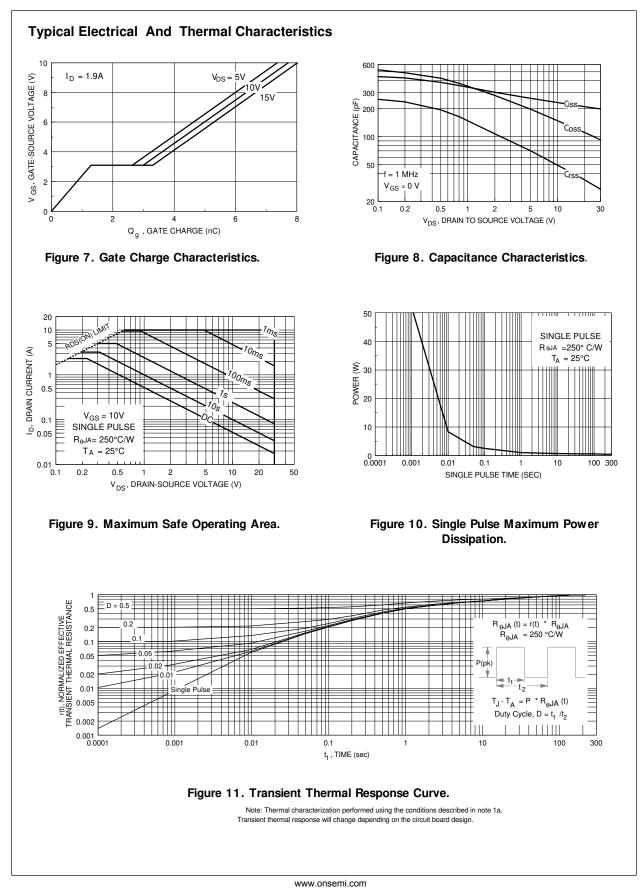
Typical $R_{_{BM}}$ using the board layouts shown below on 4.5"x5" FR-4 PCB in a still air environment :



۱ ۲ b. 270°C/W when mounted on a 0.001 in² pad of 2oz Cu.

2. Pulse Test: Pulse Width \leq 300µs, Duty Cycle \leq 2.0%.





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